


<b>Search Notes</b>  	<b>Application/Control No.</b>  10696051	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN, SU
	<b>Examiner</b>  Weisz, David G	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner
436	127,129,173 (text limited)	4/21/2011	/DW/

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST text search (see search history), Updated Google text search (18O, internal standard, organic acid), Inventor search in PALM	4/21/2011	/DW/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
436	127, 129, 173	4/21/2011	/DW/

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